

Notice of References Cited

Application/Control No.

09/311,313

Applicant(s)/Patent Under

Reexamination
MCBRIDE, JOHN G

Examiner

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Art Unit

2825

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Kuhns, "Automating Testability Analysis of Analog Circuits and Systems," IEEE 1992, pages 225-231.			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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